

Search Notes

Application/Control No.

10/631,319

Examiner

Y Quach Lee

Applicant(s)/Patent under
Reexamination

RHEE, SHIN W.

Art Unit

2875

SEARCHED

| Class | Subclass | Date | Examiner |
|-------|-------------------|-----------|----------|
| 362 | Updated Search | 2/22/2005 | YMY |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
|-------|----------|-----------|----------|
| 362 | Above | 2/22/2005 | YMY |
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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
|------|-----------|------|
| NONE | 2/22/2005 | YMY |
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